



Integrated Device Technology, Inc.

FAST CMOS BUFFER/CLOCK DRIVER

IDT49FCT805BT/CT
IDT49FCT806BT/CT

FEATURES:

- 0.5 MICRON CMOS Technology
- Guaranteed low skew < 500ps (max.)
- Very low duty cycle distortion < 600ps (max.)
- Low CMOS power levels
- TTL compatible inputs and outputs
- TTL level output voltage swings
- High drive: -32mA IOH, 48mA IOL
- Two independent output banks with 3-state control
- 1:5 fanout per bank
- 'Heartbeat' monitor output
- ESD > 2000V per MIL-STD-883, Method 3015;
> 200V using machine model (C = 200pF, R = 0)
- Available in DIP, SOIC, SSOP, QSOP, Cerpack and LCC packages

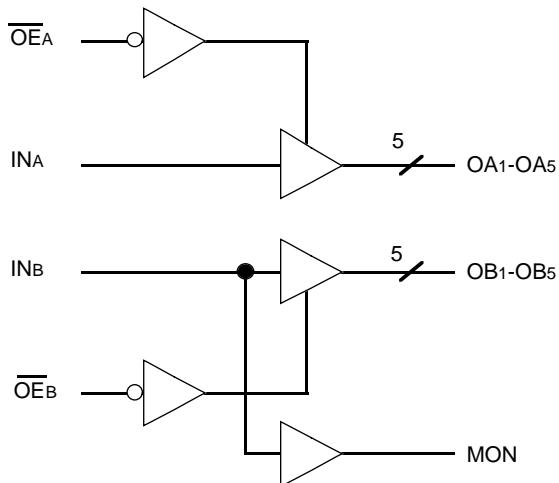
- Military product compliant to MIL-STD-883, Class B

DESCRIPTION:

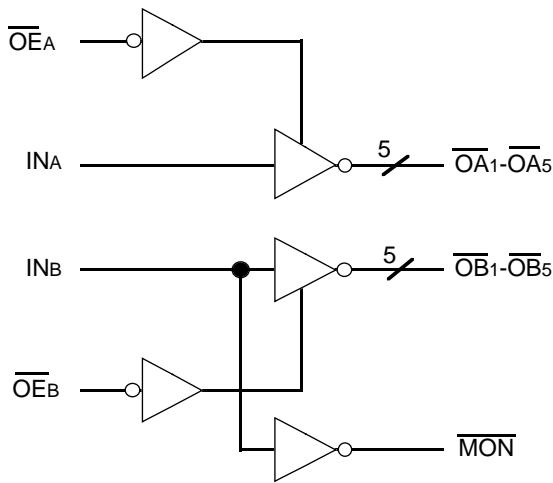
The IDT49FCT805BT/CT and IDT49FCT806BT/CT are clock drivers built using advanced dual metal CMOS technology. The IDT49FCT805BT/CT is a non-inverting clock driver and the IDT49FCT806BT/CT is an inverting clock driver. Each device consists of two banks of drivers. Each bank drives five output buffers from a standard TTL compatible input. The 805BT/CT and 806BT/CT have extremely low output skew, pulse skew, and package skew. The devices has a "heartbeat" monitor for diagnostics and PLL driving. The MON output is identical to all other outputs and complies with the output specifications in this document. The 805BT/CT and 806BT/CT offer low capacitance inputs with hysteresis.

FUNCTIONAL BLOCK DIAGRAMS

IDT49FCT805T



IDT49FCT806T



2920 drw 01

2920 drw 02

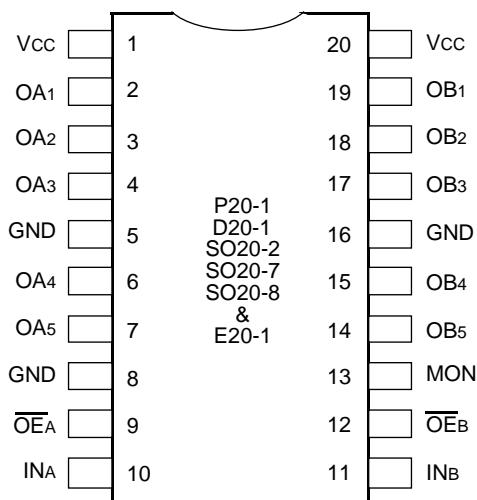
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MILITARY AND COMMERCIAL TEMPERATURE RANGES

OCTOBER 1995

PIN CONFIGURATIONS

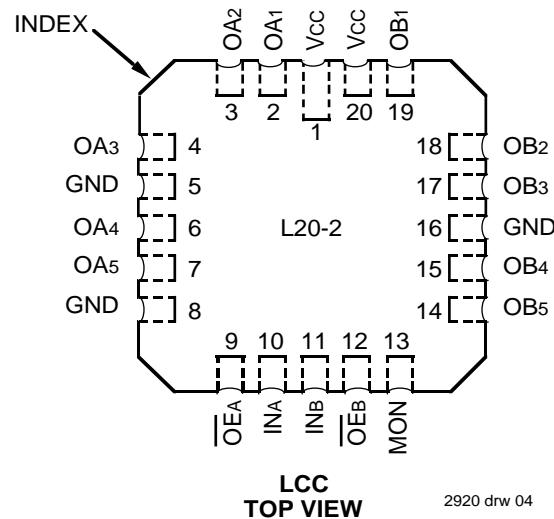
IDT49FCT805T



DIP/SOIC/SSOP/QSOP/CERPACK

TOP VIEW

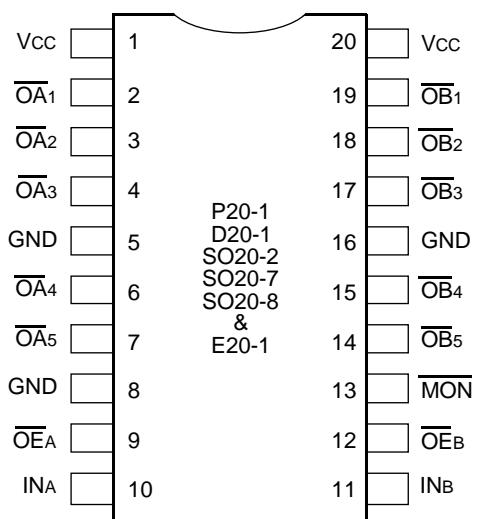
2920 drw 03



LCC
TOP VIEW

2920 drw 04

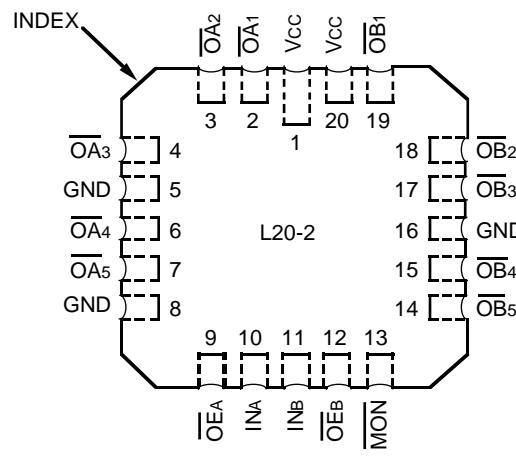
IDT49FCT806T



DIP/SOIC/SSOP/QSOP/CERPACK

TOP VIEW

2920 drw 05



LCC
TOP VIEW

2920 drw 06

PIN DESCRIPTION

Pin Names	Description
OE _A , OE _B	3-State Output Enable Inputs (Active LOW)
INA, INB	Clock Inputs
OA _n , OB _n	Clock Outputs (FCT805T)
OA _n , OB _n	Clock Outputs (FCT806T)
MON	Monitor Output (FCT805T)
MON	Monitor Output (FCT806T)

2920 tbl 01

FUNCTION TABLE⁽¹⁾

Inputs		Outputs			
		49FCT805T		49FCT806T	
OE _A , OE _B	INA, INB	OA _n , OB _n	MON	OA _n , OB _n	MON
L	L	L	L	H	H
L	H	H	H	L	L
H	L	Z	L	Z	H
H	H	Z	H	Z	L

NOTE:

1. H = HIGH, L = LOW, Z = High Impedance

2920 tbl 02

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Rating	Commercial	Military	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
VTERM ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to Vcc +0.5	-0.5 to Vcc +0.5	V
TA	Operating Temperature	0 to +70	-55 to +125	°C
TBIAS	Temperature Under Bias	-55 to +125	-65 to +135	°C
TSTG	Storage Temperature	-55 to +125	-65 to +150	°C
IOUT	DC Output Current	-60 to +120	-60 to +120	mA

NOTES:

2920 Ink 03

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed Vcc by +0.5V unless otherwise noted.
- Input and Vcc terminals.
- Output and I/O terminals.

2920 Ink 04

CAPACITANCE ($T_A = +25^\circ\text{C}$, $f = 1.0\text{MHz}$)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C_{IN}	Input Capacitance	$V_{IN} = 0\text{V}$	4.5	6.0	pF
C_{OUT}	Output Capacitance	$V_{OUT} = 0\text{V}$	5.5	8.0	pF

NOTE:

1. This parameter is measured at characterization but not tested.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified

Commercial: $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = 5.0\text{V} \pm 5\%$; Military: $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$, $V_{CC} = 5.0\text{V} \pm 10\%$

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V_{IH}	Input HIGH Level	Guaranteed Logic HIGH Level		2.0	—	—	V
V_{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I_{IH}	Input HIGH Current ⁽⁵⁾	$V_{CC} = \text{Max.}$	$V_I = 2.7\text{V}$	—	—	± 1	μA
I_{IL}	Input LOW Current ⁽⁵⁾	$V_{CC} = \text{Max.}$	$V_I = 0.5\text{V}$	—	—	± 1	μA
I_{OZH}	High Impedance Output Current	$V_{CC} = \text{Max.}$ (3-State Output pins) ⁽⁵⁾	$V_O = 2.7\text{V}$	—	—	± 1	μA
I_{OZL}			$V_O = 0.5\text{V}$	—	—	± 1	μA
I_I	Input HIGH Current ⁽⁵⁾	$V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$		—	—	± 1	μA
V_{IK}	Clamp Diode Voltage	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$		—	-0.7	-1.2	V
I_{OS}	Short Circuit Current	$V_{CC} = \text{Max.}^{(3)}, V_O = \text{GND}$		-60	-120	-225	mA
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -12\text{mA MIL.}$ $I_{OH} = -15\text{mA COM'L.}$	2.4	3.3	—	V
			$I_{OH} = -24\text{mA MIL.}$ $I_{OH} = -32\text{mA COM'L.}^{(4)}$	2.0	3.0	—	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 32\text{mA MIL.}$ $I_{OL} = 48\text{mA COM'L.}$	—	0.3	0.55	V
I_{OFF}	Input/Output Power Off Leakage ⁽⁵⁾	$V_{CC} = 0\text{V}, V_{IN}$ or $V_O \leq 4.5\text{V}$		—	—	± 1	μA
V_H	Input Hysteresis for all inputs	—		—	150	—	mV
I_{CCL} I_{CCH} I_{CCZ}	Quiescent Power Supply Current	$V_{CC} = \text{Max.}, V_{IN} = \text{GND}$ or V_{CC}		—	5	500	μA

NOTES:

2920 Ink 05

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 5.0\text{V}$, $+25^\circ\text{C}$ ambient.
- Not more than one output should be tested at one time. Duration of the test should not exceed one second.
- Duration of the condition can not exceed one second.
- The test limit for this parameter is $\pm 5\mu\text{A}$ at $T_A = -55^\circ\text{C}$.

POWER SUPPLY CHARACTERISTICS

	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	V _{CC} = Max. V _{IN} = 3.4V ⁽³⁾		—	0.5	2.0	mA
I _{CCD}	Dynamic Power Supply Current ⁽⁴⁾	V _{CC} = Max. Outputs Open $\overline{OE}_A = \overline{OE}_B = GND$ 50% Duty Cycle	V _{IN} = V _{CC} V _{IN} = GND	—	60	100	$\mu A / MHz/bit$
I _C	Total Power Supply Current ⁽⁶⁾	V _{CC} = Max. Outputs Open f _O = 25MHz 50% Duty Cycle $\overline{OE}_A = \overline{OE}_B = V_{CC}$ Mon. Output Toggling	V _{IN} = V _{CC} V _{IN} = GND	—	1.5	3.0	mA
		V _{IN} = 3.4V V _{IN} = GND	—	1.8	4.0		
		V _{IN} = V _{CC} V _{IN} = GND	—	33	55.5 ⁽⁵⁾		
		V _{IN} = 3.4V V _{IN} = GND	—	33.5	57.5 ⁽⁵⁾		

NOTES:

2920 tbl 06

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at V_{CC} = 5.0V, +25°C ambient.3. Per TTL driven input; (V_{IN} = 3.4V); all other inputs at V_{CC} or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.

5. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.6. I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}I_C = I_{CC} + $\Delta I_{CC} D_{HNT} + I_{CCD}$ (f_ONo)I_{CC} = Quiescent Current (I_{CC1}, I_{CC2} and I_{CC3}) ΔI_{CC} = Power Supply Current for a TTL High Input (V_{IN} = 3.4V)D_H = Duty Cycle for TTL Inputs HighN_T = Number of TTL Inputs at D_HI_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)f_O = Output FrequencyNo = Number of Outputs at f_O

All currents are in millamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE^(3,4)

Symbol	Parameter	Condition ⁽¹⁾	IDT49FCT805BT/806BT				IDT49FCT805CT/806CT				Unit	
			Com'l.		Mil.		Com'l.		Mil.			
			Min. ⁽²⁾	Max.								
tPLH tPHL	Propagation Delay INA to OAn, INB to OBn	CL = 50pF RL = 500Ω	1.5	5.0	1.5	5.7	1.5	4.5	1.5	5.2	ns	
tR	Output Rise Time		—	1.5	—	2.0	—	1.5	—	2.0	ns	
tF	Output Fall Time		—	1.5	—	1.5	—	1.5	—	1.5	ns	
tsk(o)	Output skew: skew between outputs of all banks of same package (inputs tied together)		—	0.7	—	0.9	—	0.5	—	0.7	ns	
tsk(p)	Pulse skew: skew between opposite transitions of same output (tPHL-tPLH)		—	0.7	—	0.9	—	0.6	—	0.8	ns	
tsk(t)	Package skew: skew between outputs of different packages at same power supply voltage, temperature, package type and speed grade		—	1.2	—	1.5	—	1.0	—	1.2	ns	
tPZL tPZH	Output Enable Time OE _A to OAn, OE _B to OBn		1.5	6.0	1.5	6.5	1.5	5.0	1.5	6.0	ns	
tPLZ tPHZ	Output Disable Time OE _A to OAn, OE _B to OBn		1.5	6.0	1.5	6.5	1.5	5.0	1.5	6.0	ns	

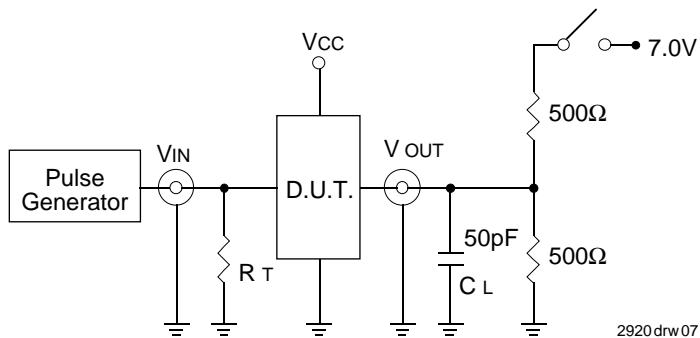
NOTES:

1. See test circuits and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. tPLH, tPHL, tsk(t) are production tested. All other parameters guaranteed but not production tested.
4. Propagation delay range indicated by Min. and Max. limit is due to Vcc, operating temperature and process parameters. These propagation delay limits do not imply skew.

2920 tbl 07

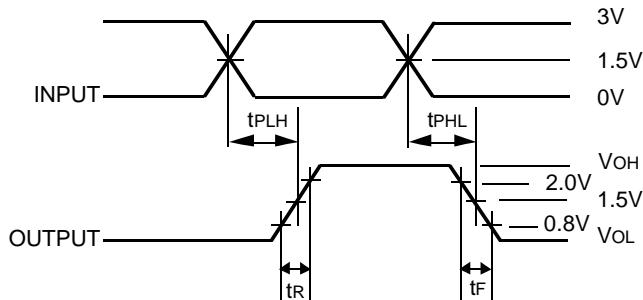
TEST CIRCUITS AND WAVEFORMS

TEST CIRCUIT FOR ALL OUTPUTS



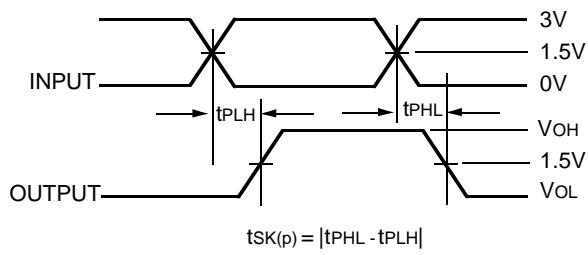
2920 drw 07

PACKAGE DELAY



2920 drw 08

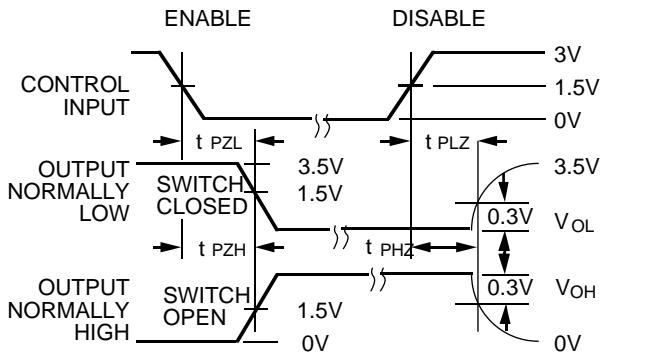
PULSE SKEW - $t_{SK}(p)$



$t_{SK}(p) = |tPHL - tPLH|$

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ENABLE AND DISABLE TIMES



2920 drw 12

NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
2. Pulse Generator for All Pulses: $f \leq 1.0\text{MHz}$; $t_F \leq 2.5\text{ns}$; $t_R \leq 2.5\text{ns}$

ENABLE AND DISABLE TIME SWITCH POSITION

Test	Switch
Disable LOW	Closed
Enable LOW	Open
Disable HIGH	Closed
Enable HIGH	Open

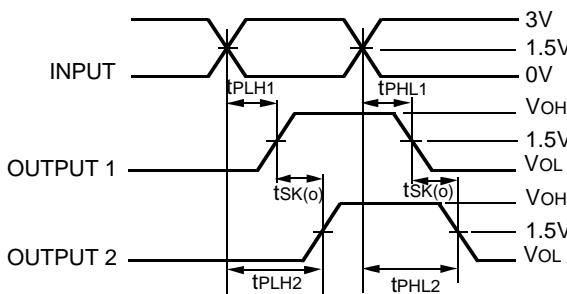
2920 Ink 08

DEFINITIONS:

C_L = Load capacitance: includes jig and probe capacitance.

R_T = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator.

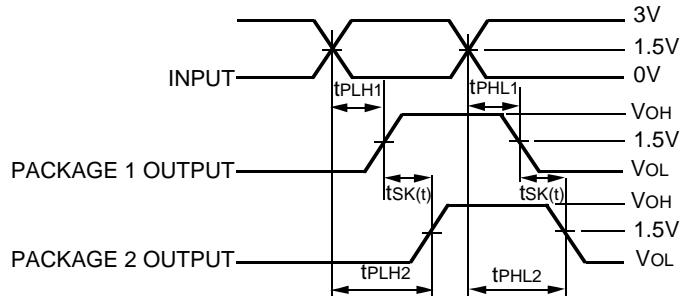
OUTPUT SKEW- $t_{SK}(o)$



$t_{SK}(o) = |tPLH2 - tPLH1|$ or $|tPHL2 - tPHL1|$

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PACKAGE SKEW - $t_{SK}(t)$

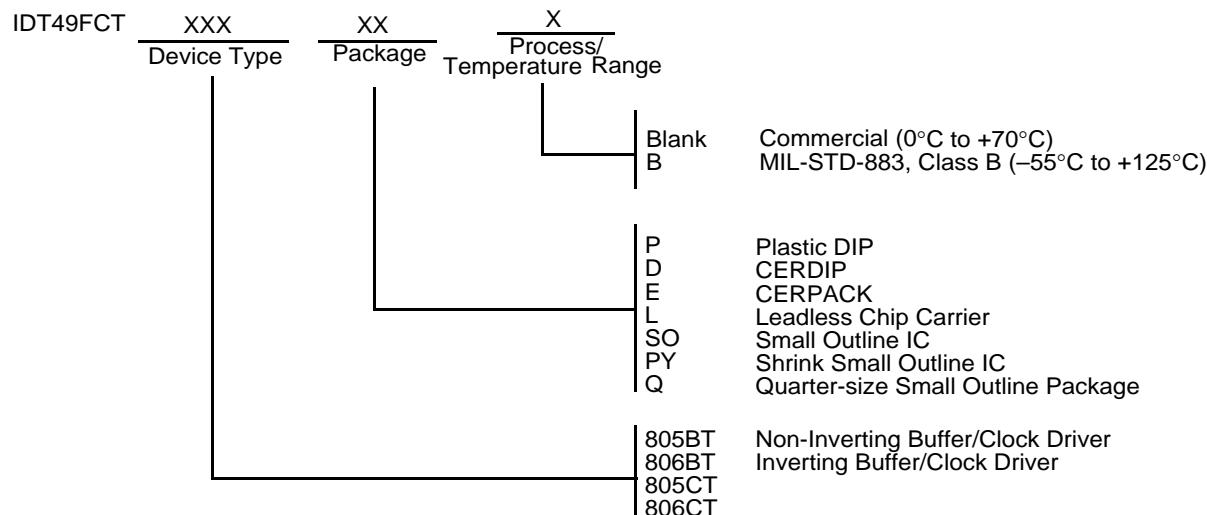


$t_{SK}(t) = |tPLH2 - tPLH1|$ or $|tPHL2 - tPHL1|$

Package 1 and Package 2 are same device type and speed grade

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ORDERING INFORMATION



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